



INFORMATION DISCLOSURE CITATION IN AN APPLICATION 				ATTY. DOCKET NO. 61282-011		SERIAL NO. 09/801,200	
				APPLICANT Kenji SHIMAZAKI, et al.			
				FILING DATE March 08, 2001		GROUP 2857	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
8	5,903,477	5/11/1999	Otsu et al.			RECEIVED OCT 11 2002 TECHNOLOGY CENTER 2800	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
8	2001-22813	1/26/2001	Japan (w/ English Abstract)				
	DE19816192A1	4/8/1999	Germany				
	DE19826236A1	6/2/1999	Germany				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			
				6/17/06			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)	ATTY. DOCKET NO. 061282-0011	SERIAL NO. 09/801,200
	APPLICANT Kenji SHIMAZAKI, et al.	
	FILING DATE March 08, 2001	GROUP 2128

U.S. PATENT DOCUMENTS

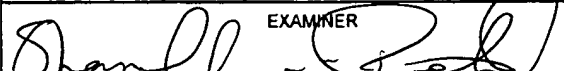
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
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FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number &-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
		JP 2000-174087 A	06/23/2000	TOSHIBA CORP.		Yes	No
						JAPAN (w/ English abstract)	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
8		HAYASHI, SACHIO et al.: "EMI-Noise Analysis Under ASIC Design Environment," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Vol. 19, No.11, November 2000, pp. 1337-1346	

 EXAMINER	6/14/06 DATE CONSIDERED
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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

 ATTY. DOCKET NO.
61282-011

SERIAL NO.

 APPLICANT
Kenji SHIMAZAKI, et al.

 FILING DATE
March 08, 2001

GROUP

 J1044 U.S. PTO
 09/801200

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
W	5,412,589	5/2/95	Williams et al.			
S	5,675,832	10/7/97	Ikami et al.			
A	5,699,263	12/16/97	Nakao			

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

W	"di/dt Noise in CMOS Integrated Circuits", by Patrik Larsson, Analog Integrated Circuits and Signal Processing, Vol. 14 (1997), pp. 113-129.
S	"EMI-Noise Analysis Under ASIC Design Environment", by Sachio Hayashi et al., International Symposium on Physical Design (1999), pp. 16-21.
S	"Power Supply Noise Analysis Methodology for Deep-Submicron VLSI Chip Design", by Howard Chen et al., DAC97, pp. 1-6.
S	"Design Methodologies for Noise in Digital Integrated Circuits", by Kenneth Shepard, DAC98 (June 1998).

EXAMINER



DATE CONSIDERED

6/17/06

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